

<b>Notice of References Cited</b>	Application/Control No. 10/530,220	Applicant(s)/Patent Under Reexamination ENOKIDO ET AL.	
	Examiner G. Nagesh Rao	Art Unit 1722	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,739,796	04-1998	Jasper et al.	343/895
*	B	US-7,224,862	05-2007	Noda et al.	385/24
*	C	US-7,136,561	11-2006	Enokido, Yasushi	385/129
*	D	US-7,184,642	02-2007	Hoshi et al.	385/129
*	E	US-7,158,710	01-2007	Zhou, Weimin	385/129
*	F	US-7,155,087	12-2006	Suh et al.	385/27
*	G	US-7,120,344	10-2006	Noda et al.	385/129
*	H	US-6,996,319	02-2006	Noda et al.	385/129
*	I	US-6,898,362	05-2005	Forbes et al.	385/132
*	J	US-6,738,551	05-2004	Noda et al.	385/130
*	K	US-6,560,006	05-2003	Sigalas et al.	359/321
*	L	US-6,366,392	04-2002	Tokushima, Masatoshi	359/321
*	M	US-6,728,457	04-2004	Sigalas et al.	385/125

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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